

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/759,339	BECKER ET AL.
	Examiner	Art Unit
	Hiep Nguyen	2816

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
<i>See P&P PUB Search</i>		<i>10-20-05</i>	